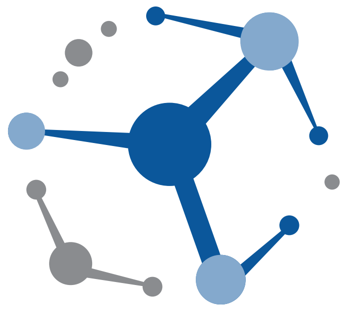

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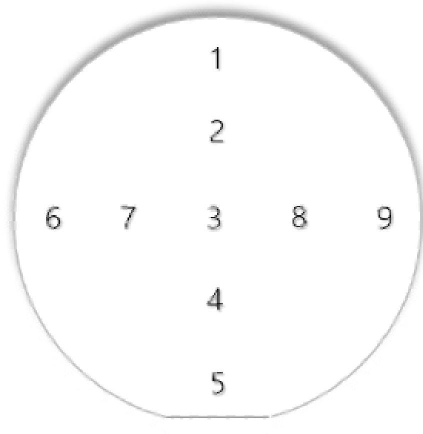
AT Series Templates

Wafer Map



Interferometer and XRD measurements

- Performed at 9 locations for 4″
- Performed at 5 locations for 2″

3333 W Pawnee St
Wichita, KS 67213
nitrideglobal.com

[AT100-SX]

Sapphire Options

Wafer Diameter	4″
Orientation	+0.2°
Backside Roughness	fine ground, polished

AlN

Orientation (major flat)	m-plane (AlN)
Thickness *(measured by interferometry)**	
Avg	0.45 µm ± 0.05 µm
WIWNU (s/Avg)	<4%
Crystal Quality (FWHM)*	
[002] XRD Linewidth	< 100 arcsec
[102] XRD Linewidth	< 325 arcsec
Transmission	>80% (@ 280 nm)
Exclusions Zone	3 mm
Surface Morphology	
Wyko Measurement (Ra)	< 3 nm

[AT50-AX]

Sapphire Options

Wafer Diameter	2″
Orientation	+0.2°
Backside Roughness	fine ground

AlN

Orientation (major flat)	m-plane (AlN)
Thickness *(measured by interferometry)**	
Avg	0.45 µm ± 0.05 µm
WIWNU (s/Avg)	<2%
Crystal Quality (FWHM)*	
[002] XRD Linewidth	< 100 arcsec
[102] XRD Linewidth	< 340 arcsec
Transmission	>80% (@ 280 nm)
Exclusions Zone	3 mm
Surface Morphology	
Wyko Measurement (Ra)	< 1 nm